## Notice of References Cited Application/Control No. 10/687,743 Examiner Thao X Le Applicant(s)/Patent Under Reexamination SAKAGUCHI ET AL. Art Unit Page 1 of 1

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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICACING) (Use several sheety if necessary)				APPLICANT KIYOFUMI SAKAGUCHI, ET AL.						
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FORM PTO 1449 (modified) APPLICATION NO. 00862.022497.1 10/687,743 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE APPLICANT LIST OF REFERENCES CITED BY APPLICANT(S)
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